

**Search Notes**

Application/Control No.

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Examiner

Hai C. Pham

Applicant(s)/Patent under  
Reexamination

KOMIYA ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	144-145, 239-240, 251-255	11/18/2005	HP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
347	239, 255	11/18/2005	HP
PGPub Text Search		11/18/2005	HP

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Text Search	11/18/2005	HP